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IC-CAP 2014.04 HF3

DynaFET Modeling



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Python

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In 1995, Guido continued his work on Python at the Corporation for National Research Initiatives (CNRI, see http://www.cnri.reston.va.us) in Reston, Virginia where he released several versions of the software.

In May 2000, Guido and the Python core development team moved to BeOpen.com to form the BeOpen PythonLabs team. In October of the same year, the PythonLabs team moved to Digital Creations (now Zope Corporation, see http://www.zope.com). In 2001, the Python Software Foundation (PSF, see http://www.python.org/psf/) was formed, a non-profit organization created specifically to own Python-related Intellectual Property. Zope Corporation is a sponsoring member of the PSF.

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Julian Seward, jseward@bzip.org bzip2/libbzip2 version 1.0.5 of 10 December 2007

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Mersenne Twister

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A C-program for MT19937, with initialization improved 2002/1/26. Coded by Takuji Nishimura and Makoto Matsumoto.

Before using, initialize the state by using init_genrand(seed) or init_by_array(init_key, key_length).

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L. Peter Deutsch ghost@aladdin.com

Independent implementation of MD5 (RFC 1321).

This code implements the MD5 Algorithm defined in RFC 1321, whose text is available at http://www.ietf.org/rfc/rfc1321.txt

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The original and principal author of md5.h is L. Peter Deutsch <ghost@aladdin.com>. Other authors are noted in the change history that follows (in reverse chronological order):

2002-04-13 lpd Removed support for non-ANSI compilers; removed references to Ghostscript; clarified derivation from RFC 1321; now handles byte order either statically or dynamically. 1999-11-04 lpd Edited comments slightly for automatic TOC extraction. 1999-10-18 lpd Fixed typo in header comment (ansi2knr rather than md5); added conditionalization for C++ compilation from Martin Purschke <purschke@bnl.gov>. 1999-05-03 lpd Original version.

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pywin32

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The following topics describe the DynaFET Modeling Package.

- Introduction to DynaFET
- Using the DynaFET Modeling Package
- Understanding the DynaFET Extraction Package Window
- Project Definition
- Data Acquisition
- De-embedding
- Extraction of Extrinsic Elements
- Intermediate Review
- ANN Model Generation
- Model Validation
- Step-by-step Procedure to Extract a DynaFET Model

Watch the recorded webcast to learn more about DynaFET.

Introduction to DynaFET

DynaFET is a non-quasi static large-signal FET model. It incorporates self-heating and other multiple timescale dynamics necessary to describe the large-signal behavior of III-V FET technologies including GaAs and GaN. It uses Artificial Neural Networks (ANNs) to model the I-V and Q-V relations in a general way. The ANN is trained on non-linear waveforms measured on a non-linear vector network analyzer (NVNA). The NVNA waveforms are measured over the entire device operation range in such a way that the device integrity is not compromised.

The model supports geometrical scaling rule(s) and so measurement of just one device can be scaled to other gate widths.

The key features and benefits of the DynaFET are listed in the table below.

Feature	Benefit
Dynamic self-heating and ambient temperature- dependence	Accuracy versus temperature; thermal memory modeled
Gate-lag and drain-lag independently modeled (knee walk-out, power slump)	Power slump, bias current versus Pin, and PAE well modeled
Aritificial neural networks (ANNs) for very general, smooth I-V / Q-V relations	Details non-linear coupling of trap states to current accurately and smoothly modeled. Model does not need to know detailed physics-ideal for new and changing processes
NVNA non-linear data for model generation and independent non-linear validation	Data over entire operating range while maintaining device safety; NVNA data closer to actual size condition
Simple geometrical scaling	Same as standard expectations for a copact time-domain transistor model

The DynaFET model is comprised of a conventional parasitic network surrounding the intrinsic model. The topology of the model is depicted in the following figure.



The intrinsic model contains the ANN and a self-heating circuit, and a gate and drain circuits to represent the gate and drain traps. These circuits provide inputs to calculate auxiliary variables. The auxiliary variables, along with the input non-linear waveforms are used to train the ANN. The following figure depicts the Auxiliary circuits used in the intrinsic DynaFET model.



DynaFET Extraction Flow

The following figure depicts the functional relationship of measurements and model.



The IC-CAP DynaFET module manages the data measured by the non-linear vector network analyzer as well as data from measurements it made. The IC-CAP module also trains the ANN and outputs the necessary files for the ADS implementation to reference.

The DynaFET Extraction Package generates a model from the DC, S-Parameters, and large-signal waveform data. The DynaFET Package works with the software on the PNA-X to acquire non-linear waveform data. It then extracts the parasitic network elements, trains the Artificial Neural Network, then presents the results for validation against other measurements. Finally, it generates a model file that is compatible with the DynaFET implementation in ADS (versions ADS2014 and later).

The package comprises the key procedural steps in the DynaFET extraction flow, as depicted in the following figure:

- Data (Daq) Acquisition: Measures DC, S Parameters and copies the NVNA data file to the project directory.
- **De-embedding**: Executes de-embedding with flexible configuration.
- Extraction of Extrinsic Elements: Extracts extrinsic linear elements.
- Intermediate Review: Performs data sanity check by generating a Root model.
- ANN Model Generation: Extracts the core model Artificial Neural Network.
- Model validation: Models the simulated results against measured data that was not part of the model fitting data set.



Each step is expected to be executed sequentially. The output of each step are data files, stored locally in the project, which are used by subsequent steps. If you return to a previous step, it is mandatory to repeat the steps that follow as well. A detailed DynaFET mode extraction flow is depicted in the following figure.



In the above figure, the red lines indicate the data measured by the IC-CAP DynaFET program.

The IC-CAP DynaFET module manages the complex data generated by the non-linear vector network analyzer, measures linear DC and S-Parameters, and then, using additional information you have supplied, trains the ANN. The model output is an encrypted file that is used by the ADS DynaFET model.

Project Structure

The following table displays the project structure (created when the DynaFET example is copied to your working directory).

/\$project_root	
/config	hardware setting, model card for simulation
/daq	data files generated by data acquisition

/deem	data files generated by de-embedding
/extraction	intrinsic data
/review	root model data
/ann	ann training data
/qg	
/model	ann weights for model generation of Qg
/test	test ann weights
/sweep	sweep ann weights
/qd	
/model	ann weights for model generation of Qd
/test	test ann weights
/sweep	sweep ann weights
/ig	
/model	ann weights for model generation of Ig
/test	test ann weights
/sweep	sweep ann weights
/id	
/model	ann weights for model generation of Id
/test	test ann weights
/sweep	sweep ann weights
/validation	DynaFET model card

Using the DynaFET Modeling Package

A detailed description of using the DynaFET modeling package is found in "STEP-BY-STEP PROCEDURE FOR MEASURING AND EXTRACTING A DYNAFET MODEL".

To launch the DynaFET modeling package:

- Select File > Examples from the IC-CAP main window. The File Open dialog box is displayed.
- 2. Select the DynaFET.mdl model file available under model_files > mesfet > dynafet folder.
- 3. Click Open.

An icon of the DynaFET.mdl model file is displayed in the IC-CAP main window.



4. Double-click the DynaFET.mdl icon.

The Copy DynaFET Example Project dialog box is displayed.

Project Loca	tion	
Name	untitled	
Created in	C:\jccap_project	Browse
		OK Cancel

5. Specify the project Name and click Browse to select the project location.

6. Click **OK** to copy the example to your local working directory.

The DynaFET Extraction Package window is displayed. For information on the extraction window, see

Jnderstanding the DynaFET Extraction Package Window.						
File Help						
📊 🐻 🗭 🎉 🚥 Running Mode	📊 🚟 🟈 🎇 🚥 Running Mode: Measurement 🔍					
Project A Data Acquisition	Project					
DC Series Resistance	Ø					
Cold-FET SP	Project Directory					
Broadband SP for model v DC SP for model generation	C:/workarea/IC-CAP/dynafet/test_dynaFET/test					
Input NVNA Data	Device Info					
De-embedding	Device ID		device_01			
Execute default extraction	Chip ID		chip_01			
Input of Custom Values	Process					
Intermediate review	Mask					
Root model state functions	Wafer					
ANN model generation	Total Gate Width	[m]	0.0001	100.0 [um]		
Qg	# of Fingers		2			
Iq	Rchan	[Ohm-m]	0.000155			
Id	Rth	[deg C/W]	450			
Model Validation	Thermal Time Constant	[s]	0.0001			
DC SP					Import Export	

Understanding the DynaFET Extraction Package Window

The DynaFET Project window allows you to save the project configuration and perform various project settings for a DynaFET model. The following figure depicts the DynaFET Extraction Package window that is displayed after entering the project name and directory.

rile nelp						
📊 🧱 🕢 🎉 🚥 Running Mode: Measurement 👻						
 Project Data Acquisition DC Series Resistance Pinched-off SP Cold-FET SP Broadband SP for model v DC SP for model generation 	Project Ø Project Directory C:/workarea/IC-CAP/dynafet/test_dynaFET/test					
Input NVNA Data De-embedding 4 Extraction of Extrinsic Elements Execute default extraction Input of Custom Values 4 Intermediate review Intrinsic elements vs freque Root model state functions 4 ANN model ageneration	Device Info Device ID Chip ID Process Mask Wafer Total Gate Width	[m]	device_01 chip_01	100.0 fum1		
Qg Qd Ig Id Model Validation DC SP	≠ of Fingers Rchan Rth Thermal Time Constant	[Ohm-m] [deg C/W] [s]	2 0.000155 450 0.0001	Import	Export	

The DynaFET Extarction Package window mainly consists of the following parts:

- 1. DynaFET Menu Bar: Provides options to create, open, save a DynaFET model file, and to access documentation.
- 2. **DynaFET Toolbar**: Provides shortcuts for commonly used commands, such as opening the hardware window, saving a project configuration, and plot options.
- 3. Navigation View: Displays project options as a hierarchical list of task flow in a project.
- 4. Workspace Window: A context dependent area, which changes according to the project action selected from the Navigation View.
DynaFET Menu Bar

The following menus are available in the DynaFET Extraction Package window.

- File: Allows you to create a new project, open an existing project, save the project, or copy an example under a working directory.
- Help: Allows you the access the DynaFET Modeling documentation.

DynaFET Toolbar

The following table describes the main DynaFET toolbar options. You can view or hide the toolbars toggle by rightclicking on the toolbar and selecting the **DynaFET ToolBar** option.

Option	Icon	Description
Save		Saves a project configuration
Open Hardware Window		Opens the hardware setup window
Open Simulation Debugger		Opens the simulation debugger window
Close All Plots		Closes all the plots for a project
Stop All ANN	STOP	Stops all the artificial neural networks for a project
Running Mode	Running Mode: Measurement 🔻	MeasurementSimulation

Navigation View

DynaFET Modeling User Interface provides a tree-structured representation of the project with various components like data acquisition, de-embedding, etc. You can use the navigation view to perform various project settings. Typically, the parent page either provides some general information about the step, or settings that apply to all the sub-steps in that main step.

Note that if you go back to a previous step and re-execute any function or change a value, you must re-execute the steps following that step. Going to a prior step and re-displaying information does not require re-executing the other steps.

The following figure displays the Navigation View.

- ▲ Project
 - Data Acquisition

DC Series Resistance Pinched-off SP Cold-FET SP Broadband SP for model validation DC SP for model generation Input NVNA Data De-embedding

- Extraction of Extrinsic Elements Execute default extraction Input of Custom Values
- Intermediate review
 Intrinsic elements vs frequency
 Root model state functions vs bias
- ANN model generation
 - Qg
 - Qd
 - Ig
 - Id
- Model Validation
 - DC
 - SP

The Navigation view consist of the following:

- Data Acquisition
- De-embedding
- Extraction of Extrinsic Elements
- Intermediate Review
- ANN Model Generation
- Model Validation

Workspace Window

The workspace window provides a display and entry fields that are appropriate for the particular step that is active in the Navigation Window.

The following figure displays the Workspace Window.

Project		
Ø		
Project Directory		
C:/workarea/IC-CAP/dynafet/te	st_dynaFET/test	Browse
Device Info		
Device ID	device_01	
Chip ID	chip_01	
Process		
Mask		
Wafer		
Total Gate Width [m]	0.0001	100.0 [um]
# of Fingers	2	
Rchan [Ohm-m]	0.000155	
Rth [deg C/W]	450	
Thermal Time Constant [s]	0.0001	
		Import Export

The following table describes the options available in the workspace window.

Option	Description
Project Directory	Displays the example project location.
Device Info	Displays the device information.

Each window contain icons to execute various tasks and these icons vary depending on the selection . For example,

icon is available in the **Pinched-off SP** workspace window (depicted below) and is used to clear the data values for

a particular step.

Pinched-of	if SP		
👎 Ø	Fe 🖆 🔚		
Frequency [Hz]	Vd [V]	Vg [V]
Start	500MEG	Value 0	Value -5
Stop	50G		
# of Points	100		
Step	500MEG		

NOTE

The workspace window contain few grayed out fields that are uneditable.

Project Definition

The project step provides an interface, **Project** workspace, to enter information about the device, as depicted in the following figure.

Project		
Ø		
Project Directory		
C:/iccap_project/t	est/daq	
Device Info		
Device ID	device_01	
Chip ID	xxx	
Process		
Mask		
Wafer		
Total Gate Width [m]	0.0001	100.0 [um]
# of Fingers	2	
Rchan	0.000155	
Rth	450	
Thermal Time Constant	0.002	

The Device ID and Chip ID are arbitrary strings, but must be defined as they are used in the file names of various data files.

Field	Description
Device ID	An arbitrary string, typically a descriptive name of the device
Chip ID	An arbitrary string used to describe a particular chip, typically an alphanumeric identifier
Process	An arbitrary string, typically a description of the process used to fabricate the device
Mask	An arbitrary string, typically indicates a mask set so as to specify geometry
Total Gate Width	The total width of the device, in meters, used by the model to scale the device
# of Fingers	The number of gate fingers in the device, used by the model to scale parasitic element values
Rchan	The channel resistance, in Ohm-mm, used by the extraction algorithms to partition access resistances

Field	Description
Rth	Thermal resistance in Deg C /-W that describes the self- heating of the device.
Thermal Time Constant	The time constant, in seconds, (Rth*Cth) that describes the thermal behavior of the device.

Project property settings are used by the program for file names and geometry calculations, but also provide a way to annotate the device.

The Process, Mask, and Wafer fields can be used to optionally store information about the device within the project.

The Total Gate Width and # of Fingers must be entered and are used during the extraction to set geometric scaling rules.

Rchan, the channel resistance, is used to help partition the Rd and Rg resistances. The thermal properties of the device are defined by Rth and the overall thermal time constant of the device. This value must be measured independently.

Data Acquisition

The data acquisition step covers all the DC and S-Parameter measurements made by IC-CAP as well as identifying and copying the non-linear waveform data files made by the PNA-X outside of the IC-CAP program. Selecting the 'Data Acquisition' page shows three tabs - Introduction, Instrument Setting, and Measurement Setting of the data acquisition step. The following figure depicts the Data Acquisition workspace displaying the short descriptions for various steps.



Instrument Setting

The Instrument Setting tab allows you to add hardware and perform the settings for the connected instrument and then load the saved settings. For information on instrument options, see Supported Instruments. For information on setting up the hardware and connecting the instruments to be measured, see Configuring Hardware and Performing Measurement.

NOTE

For most devices, it is safe to switch the gate bias before the drain bias. Therefore, it is recommended that the SMU connected to the drain be located in a lower slot number.

Instrument Setting Toolbar

The following table describes the main DynaFET toolbar options.

Option	Icon	Description
Open Hardware Window		Opens the hardware setup window
Load instrument Setting		Loads the instrument setting
Save Instrument Options		Saves instrument options

Setting up the Hardware and Instrument Settings

To set up the hardware and load the settings, do the following:

1. Click Open Hardware Window (

The IC-CAP/Hardware Setup window is displayed using which you can add, build, or configure the connected instrument. For information on the Hardware Setup window, see IC-CAP Design Environment.

- 2. Add an interface (if required) and rebuild the instrument list using the conventional IC-CAP procedures.
- 3. Click Configure... and set SMU1, SMU2, SMU3 for DC measurement and NWA for SP measurement.
 - NOTE

Drain SMU (SMU2) occurs before the Gate SMU (SMU1).

f HP4142:2		X
	-Unit Table -	
Instrument	MPSMU1	
Address 10 テ	HPSMU4	SMU2
	HPSMU6	SMU1
Car	ncel	Help
	f HP4142:2 Instrument Address 10 🜩	f HP4142:2 Unit Table MPSMU1 Address 10 HPSMU4 HPSMU6 Cancel

- 4. Click Load Instrument Setting (), to load the instrument information. The instrument information is displayed under the Instrument List page.
- 5. Select DC Source /Monitor and NWA from the available instrument list.

ntroduction Instrument Se	etting	Measurement Setting	
Instrument List		Instrument Ontions	Value
Select Instrument		in the second se	value
HP4145	1	Use User Sweep	No
AgilentPNA	2	Hold Time	0
	3	Delay Time	0
4	4	Integ Time	S
	5	Init Command	
Select DC Source/Monitor			
HP4145 •			
Select NWA			
AgilentPNA 🔻			

- 6. Set instrument options for DC and SP measurements, using the DC Source / Monitor and NWA list available on the left side of the window. Then, modify each property value for a particular instrument.
 - NOTE

You can also save these settings in a configuration file for future reference, however, this is optional depending on your requirement.

Measurement Setting

The Measurement Setting tab allows you to set Broadband Frequency sweep and Compliance setting for DC measurement. Some of these values can be overridden at the specific measurement page.

Introduction	Instrument Setting	Measurement Setting
Broadband Fi	requency Sweep [Hz]	
Start	500MEG	
Stop	50G	
# of Points	100	
Step	500MEG	
Sweep Type	LIN	
Compliance S	Setting	
Ig Compliand	e [A] 0.1	
Id Compliand	e [A] 0.5	

The Measurement Setting tab sets the default values of the frequency sweeps as well as compliance values for the SMUs. The values can be overridden on other pages.

DC Series Resistance

In this workspace, the DC Series Resistance is measured. Alternatively, you can enter (or modify) the resistance. These values are used to remove the effect of the cable resistance from the DC measurements.

DC Series Res	sistance	
🗣 Ø 🌾		
Select		
Measure		
Manual Edit		
Cable DC Series	Resistance	
Port 1 [Ohm]	0	
Port 2 [Ohm]	0	
		Sav

Save Instrument Options

The following table describes the DC Series Resistance toolbar options.

Option	lcon	Description
Measure		Performs measurement
Clear Data	Ø	Clears the resistance and device geometry data
Display Plot		Opens the plot window
Export Data		Exports data

You should lower both probes on a shorted pattern and press the Measure icon. The program then performs the measurement and update the **Cable DC Series Resistance** fields with the measured values. When a measurement is performed, the IC-CAP Status Window provides a Stop measurement button.

IC-CAP/Status	
File Interrupt	
👓 📿 🛃	

The IC-CAP Status Window is modified during a measurement to include an overall stop button. Pressing this during a measurement aborts any active measurement.

After a measurement, you can display the data with the Plot icon and inspect the I-V curves for correct behavior. The extracted values should be checked to be sure they are reasonable.

Pinched-off SP

In this workspace, the S-parameters used to determine the parasitic capacitor element values are measured (as decpited in the following figure). The values are extracted at one frequency but a broad frequency range allows inspection of how frequency-independent the result is. The drain value should be small or zero while the gate value should be sufficient to pinch off the device without causing breakdown current to flow. The following figure depicts the setup workspace for S-Parameter measurements to be used in Pinched-off extraction.

Pinched-of	f SP		
Frequency [Hz]	Vd [V]	Vg [V]
Start	500MEG	Value 0	Value -5
Stop	50G		
# of Points	100		
Step	500MEG		

The following table describes the **Pinched-off SP** toolbar options.

Option	Icon	Description
Measure		Performs measurement
Clear Data	Ø	Clears the resistance and device geometry data
Display Plot		Opens the plot window
Import Data		Imports data
Export Data		Exports data

Cold-FET SP

In this workspace, depicted below, the S-parameters for determining the inductance and resistance parasitic element values are measured using the "cold-FET" method [G. Dambrine, A. Cappy, F. Heliodore, and E. Playez, "A new method for determining the FET small-signal equivalent circuit," IEEE Trans. Microwave Theory Tech., vol. 36, pp. 1151–1159, July 1988].

The S-Parameters are measured while biasing device strong inversion but no current (Vgs >> Vt, Vds ~ 0). The drain value should be small or 0 while the gate value should be sufficient to forward bias the gate while not damaging the device. The values are extracted at one frequency but a broad frequency range allows inspection of how frequency-independent the result is. The following figure depicts the setup workspace for S-Parameter measurements to be used in Cold-FET extraction.

Cold-FET S	P		
🗣 Ø	Fe 🖆 🔚		
Frequency [Hz]	Vd [V]	Vg [V]
Start	500MEG	Value 0	Value 0.5
Stop	50G		
# of Points	100		
Step	500MEG		

The following table describes the **Cold-FET SP** toolbar options.

Option	lcon	Description
Measure		Performs measurement
Clear Data	Ø	Clears the resistance and device geometry data
Display Plot		Opens the plot window
Import Data		Imports data
Export Data		Exports data

Broadband SP for model validation

In this workspace, depicted below the measurements of broad-band S-parameter at selected bias points for validation are taken. These measurements are not be used in the extraction or training aspects of the model fitting. It is best to choose a slightly different frequency grid and bias points than what is used in the model generation procedure. The following figure depicts the workspace for broadband S-Parameter measurements used to illustrate how well model fits.

Broadband SP for model validation					
👎 Ø 🖣	a 🖆 🔚				
Frequency [H	2]	Vd [V]		Vg [V]	
Start	500MEG	Start	3.0	Start	500m
Stop	50G	Stop	5.0	Stop	-1.5
# of Points	100	# of Points	2	# of Points	5
Step	500MEG	Step	2.0	Step	-0.5
Sweep Order	1	Sweep Order	2	Sweep Order	3

The following table describes the Broadband SP for model validation toolbar options.

Option	Icon	Description
Measure		Performs measurement

Clear Data	Ø	Clears the resistance and device geometry data
Display Plot		Opens the plot window
Import Data	7	Imports data
Export Data		Exports data

The Display Plot displays the data for inspection. The following figure depicts the S-Parameters measured over various bias conditions, to be used for model validation:



DC SP for model generation

The DC SP for model generation workspace defines the settings for measuring the DC, S-Parameters for model generation. The measurements are made across the full safe operating region (SOR) of the device. The setup allows to select the bias sweeps in such a way that full coverage of the SOR is possible. For each measurement, the program first calculates the possibility that the device's compliance settings is reached. If that's the case, the program aborts the measurement for that segment and continues based on the setting of the Abort Type. The following figure depicts the workspace user interface for setting up the DC and S-Parameter linear measurements used during model generation.

🚽 🚟 🥙 🎉 🥶 Running Mode: Measu	rement 💌							
Project	DC SP for model generation							
 Data Acquisition DC Series Resistance 	S 🖉 🕾 🚔 🗖							
Pinched-off SP	*** Ø 🦷 🔚 🗖							
Cold-FET SP Broadband SP for model validation	Measurement Setting		Frequency	Setting (Hz)		Temperature Setting		
DC SP for model generation	DC Only		Start	100MEG		🖋 Temperature [C	25 🔹	Edit
Input NVNA Data	Power [W/mm] 2	hower [W/mm] 2		24.1G				
Extraction of Extrinsic Elements	I_Brk [A/mm] 0.0013		# of Point	s 41				
Execute default extraction	I_Fwd [A/mm] 0.12		Step	600MEG				
Input of Custom Values	Advan	ced Setting		Select Fre	quency			
Intrinsic elements vs frequency								
Root model state functions vs bias	Region Specification							
ANN model generation Og	Num of regions used 6							
Qd	Sequence [1] [2] [3] [4] [5] [6]	Edit					
lg Id		👩 Region 1	👩 Region 2	👩 Region 3	👩 Region 4	👩 Region 5	👩 Region 6	
 Model Validation 	Vdstart	0.0	-0.31	0.0	-0.31	-0.4	-0.3	
DC	Vilston		01	6	0.1	14.0	15.0	
34		3.3	-0-1	0	-0.1	14.9	15.0	
	Vdstep	0.3	0.3	0.3	0.3	0.3	0.3	
	Vgstart	-1.0	-1.0	0.6	0.6	-1.0	-5.0	
	Vactor	0.5	0.5		1.9	0.5	-1.1	
	ightop	0.0	0.5	1.9				
	Vastep	0.3	0.3	1.9	0.3	0.3	0.3	
	Vgstep	0.3	0.3	0.3	0.3	0.3	0.3	
	Vgstep Extension of Existing Region	0.3	0.3 0	1.9 0.3 0	0.3 0	0.3	0.3 0	
	Vgstep Extension of Existing Region Adaptive	0.3 0 No	0.3 0 No	1.9 0.3 0 No	0.3 0 No	0.3 0 No	0.3 0 No	
	Vystep Extension of Existing Region Adaptive Power Compliance = Power *	0.3 0 No 1.0	0.3 0 No 1.0	1.9 0.3 0 No 1.0	0.3 0 No 1.0	0.3 0 No 1.0	0.3 0 No 1.0	
	Vigstep Extension of Existing Region Adaptive Power Compliance = Power * Breakdown Compliance = Liptk *	0.3 0 No 1.0	0.3 0.3 0 No 1.0	19 0.3 0 No 1.0 1.0	0.3 0 No 1.0 1.0	0.3 0 No 1.0 1.0	0.3 0 No 1.0 1.0	
	Vigstep Extension of Existing Region Adaptive Power Compliance = Power * Breakdown Compliance = Lbrk * Id Compliance [A]	0.3 0 No 1.0 0.5	0.3 0.3 0 No 1.0 1.0 0.5	19 0.3 0 No 1.0 1.0 0.5	0.3 0 No 1.0 1.0 0.5	0.3 0 No 1.0 1.0 0.5	0.3 0 No 1.0 1.0	

The power compliance settings are described in the following table.

Setting	Description
Power	 Power Dissipation: Power Dissipation is the power that is converted to heat and then conducted or radiated away from the device. It is a measure of the rate at which energy is dissipated from an electrical system. For power dissipation, enter the total maximum power dissipation value in the Power (W/mm) field. Typically, this should be 2 Watts per mm of gate width for devices up to 1 mm.
I_Brk	Current Breakdown : Enter the reverse gate current breakdown value in the I_Brk(A/mm) field. Typically, 2 mA per mm of gate width.
I_Fwd	Conducting Gate Current : Enter the forward conducting gate current in I_Fwd (A/mm). Typically, 200 mA per mm of gate width.
SMU_Compliance	SMU Compliance: E nter the drain SMU maximum current compliance value in Amps. This is the maximum output current capability of the source/monitor unit (SMU) supplying the drain terminal.

Additional settings can be made using the **Daq Advanced Setting** Dialog box. Click **Advanced Setting**. The **Daq Advanced Setting** dialog box is displayed as depicted in the following figure.

🔄 Daq Advanced Setting		
Advanced		
Min_Vd_step	0.1	
Max_Vd_step	0.4	
Eps	0.1	
NoiseT [A/mm]	5e-07	
Soaking State		
DUT (No	
Vg [V]	0.1	
Vd [V]	0.1	
Time [s]	0.5	
OK Cancel		

The property values of advanced settings are described in the following table:

Advanced Setting	Description
Min_Vd_step	Min_Vd_step: Defines the step size between densely- spaced measurements in Vd space in Min_step(Vd) field
Max_Vd_step	Max_step : Defines the measurement step size, where you expect the data to be relatively linear and you do not need densely-spaced measurements in Vd space.
Eps	Epsilon: Predicts the next point to be measured. Therefore, it controls the automatic data acquisition step size. Increasing the value of epsilon, decreases the sensitivity of the automatic data acquisition.
NoiseT	Noise Threshold: For Noise threshold, enter a current threshold value in the NoiseT(A/mm) for both drain current and gate current below, which you do not need closely-spaced measurements. The automatic step-size algorithm is not used below the Noise threshold value, where measured currents are sampled at the maximum step size. A typical value is 500n amps per mm. Note:Do not set Noise threshold so small that it measures numerous points below pinch-off, wasting measurement time and storage capacity. Also, do not make it too high.

Soaking state property settings in the **Daq Advanced Setting** dialog box is listed below:

Soaking State Setting	Description
DUT	DUT : Determines whether or not to apply a soaking bias [No, Between each Vgs, Between regions]
Vg	Vg : Defines the gate bias to apply for the soak [V]
Vd	Vd : Defines the the gate bias to apply for the soak [V]
Time	Time: Denotes the time to apply the bias before measuring [Sec]

The **DC Only** check box skips the S-Parameter measurements and speed up the measurement time. This is useful to check for complete coverage of the device operating region.

The Frequency Setting sets the range and points, where S-Parameters is measured.

To set the frequency:

1. Select Frequency. The Select Measure Sequence dialog box is displayed.

Select Extraction Frequency		
Broadband Frequency List [Hz]		Frequency Sweep [Hz]
500MEG		Start
1G	Choose Start	Stop
1.5G		Stop -
2G		Step
2.5G		
3G	Chaosa Stan	
3.5G	Choose Stop	
4G		
45G T		
		OK Cancel

- 2. Set the extraction frequency.
- 3. Click OK.

The **Temperature Setting** indicates the temperature at which the measurements are made. The program does not control the temperature; this setting is so that the program embeds the temperature in the data files. The temperatures can be modified by pressing the **Edit Temperature** button and then selecting the values from the dialog box as depicted in the following figure.

To set the temperature of the data acquisition:

1. Click Edit under the Temperature Setting pane. The Edit Temperature Setting dialog box is displayed.

Edit Temperature Setting	2 X
 Ø 25 Ø 55 	Up Down
	OK Cancel

- 2. From the Edit Temperature Setting dialog box, select the required button:
 - a. Click Add, to embed a temperature in the data file.
 - or
 - b. Double-click an existing value, to edit and override the existing value.
 - c. Click Up or Down, to change the temperature sequence.
- 3. Specify the temperature and click OK. This updates the dialog box with the new or updated temperature setting.

To set the measurement sequence, do the following:

1. Click Edit under the Region Specification pane. The Change Measure Sequence dialog box is displayed.

🖳 Change Measure Sequence	8 23
Region [1] Region [2] Region [3] Region [4] Region [5] Region [6]	Lup Down
0	K Cancel

- 2. Click Up or Down, to change the measurement sequence of a region.
- 3. Click OK.

The following table describes the region specification fields and the respective values.

Vdstart, Vdstop, Vdsstep, Vgstart, Vgstop, Vgsstep	Defines the region in <i>Vds-Vgs</i> space.
Extension of Existing Region	Combines the data as one region (for plotting)
Adaptive	If set to Yes , the adaptive sampling is used. If set to No , then there is a fixed step size.
Breakdown Compliance = I_brk*	Scales the default value of I_brk by multiplying I_brk by this value.
AbortType	 The possible values are: F: Denotes the Exit region after First segment having no new data T: Denotes the The Terminate extraction, if no data found in the region. M: Denotes the Move to next segment, if no data is found in the current one.

The settings can be exported/imported or reset to default values by using the appropriate button at the bottom of the workspace.

Input NVNA Data

The program copies the existing NVNA data files to the local project for use during the model generation. Two data files (at 2 temperatures) must be identified. The temperature value is manually entered for each of the files and you can keep a track of what temperature each NVNA file is associated with. Pressing **Get File...** displays the browser dialog to select a file. When the file is copied over, the circle color changes from grey to green, indicating that the file is copied successfully.

Input NVNA D	ata			
Ø				
Data Files				
🔗 Ambient Ter	mperature #1 [C]	25	Get File	
🔗 Ambient Ter	mperature #2 [C]	55	Get File	
DC Series Resist	ance of NVNA syst	tem		
Port 1 [Ohm]	0.4			
Port 2 [Ohm]	0.4			

You must manually record the temperature associated with each measured data file and the DC resistances of the measurements.

As the NVNA measurement is a different equipment setup, the DC cable resistances are different than those measured by the IC-CAP DynaFET program during the DC and S-Parameter values. Enter the values of the cable resistances for each port in the appropriate field.

De-embedding

The De-embedding step removes the extrinsic parasitic influence from the measured data. The DynaFET modeling package provides following types of de-embedding methods:

- Open/Short
- Manifold

The following figure depicts the De-embedding workspace:



De-embedding provides two operations - execute and plot.

The program allows disabling of de-embedding certain datasets. This is provided to save time if de-embedding is repeated with changes and it is not necessary to de-embed all the data. However, you can keep track of whether data needs to be updated after any changes. The two methods of de-embedding are described below.

NOTE

Although no de-embedding method is used by the model, however, it is mandatory to execute De-

embedding (🔎). First clear Port 1 and Port 2, and Port 3 check boxes, and then click 🕨 .

Open/Short De-embedding

To execute de-embedding:

1. Select Add Open/Short option for Port 1 and Port 2 in the De-embedding workspace area. Red symbols are added to the schematic.



2. Double-click the **Open/Short** rectangular box for Port 1. The **Load Open/Short** .s2p dialog box is displayed.

Load Open/Short .s2p
Open From Browse
To C:/workarea/IC-CAP/dynafet/test/deem
Short From Browse
To C:/workarea/IC-CAP/dynafet/test/deem
Desired gate reference-plane
measure the S-parameters of the open (S_open) and short (S_short)
OK Cancel

- 3. Specify the locations for the files that contain the Open and Short S-Parameter data files (.s2p).
- 4. Click OK.
- 5. Repeat steps 1 to 4, for Port 2.
- 6. Click OK.

The following equation is used for calculating Open/Short de-embedding.

```
[T1] = [Ti]^-1 * [Tmeas] * [To]^-1
[T1] -> [Z1]
[Sv] -> [Zv]
[Zdut] = [Z1] - [zv]
[zdut] -> [Sdut]
where,
[Tmeas] is the T-parameters of device measured.
[Ti] is the T-parameters of pad/taper measured at Port1.
[To] is the T-parameters of pad/taper measured at Port2.
[Sv] is the 1-port S-parameter at Port3.
[Sdut] is the De-embedded S-parameters of the device.
```

Manifold De-embedding

Manifold de-embedding can be done on Port 1 and 2, or Port 1, 2, and 3.

1. Select Add Manifold option for **Port 1** and **Port 2** in the De-embedding workspace area. Red symbols are added to the schematic.



2. Double-click the Manifold Port 1 box.

The Load Manifold .s2p dialog box is displayed.



- 3. Specify the manifold S-parameter file.
- 4. Click OK.
- 5. Double-click the Manifold Port 2 box. The Load Manifold .s2p dialog box is displayed, as depicted in step 2.
- 6. Specify the manifold S-parameter file.

NOTE

If the drain manifold is measured or simulated in the opposite fashion, check the **reverse** box (note the change in numbering on the Drain Manifold).

7. Click OK.

In this case, the following equation is used to calculate the manifold de-embedding.

```
[Tdut] = [Ti]^-1 * [Tmeas] * [To]^-1
 where,
[Tmeas] is the T-parameters of device measured.
[Ti] is the T-parameters of pad/taper measured at Port1.
[To] is the T-parameters of pad/taper measured at Port2.
[Tdut] is the De-embedded T-parameters of the device.
```

8. If de-embedding of the Port 3 manifold is required, select Add Manifold option for Port 3 in the De-embedding workspace area. Red symbols are added to the schematic



9. Double-click the Manifold Port 3 box.

The Load Manifold .s2p dialog box is displayed.

🧾 Load	Manifold .s2p	? ×
Manifo	ld	
From		Browse
То	C:/workarea/IC-CAP/dynafet/test/deem	
	ОК	Cancel

- 10. Specify the manifold S-parameter file.
- 11. Click OK

In this case, the following equations are used to calculate the manifold de-embedding.

```
[T1] = [Ti]^-1 * [Tmeas] * [To]^-1
[T1] -> [Z1]
[Sv] -> [Zv]
[Zdut] = [Z1] - [zv]
[zdut] -> [Sdut]
where,
[Tmeas] is the T-parameters of device measured.
[Ti] is the T-parameters of pad/taper measured at Port1.
[To] is the T-parameters of pad/taper measured at Port2.
[Sv] is the 1-port S-parameter at Port3.
[Sdut] is the De-embedded S-parameters of the device.
```

Extraction of Extrinsic Elements

A DynaFET model parasitic circuit consists following two parts:

- Extrinsic Part: The parasitic extraction process in the DynaFET modeling tool extracts the parameters of the extrinsic part.
- Intrinsic Part: The ANN Model Generation process in the DynaFET modeling tool determines the characteristics of the intrinsic part. For details, see ANN Model Generation.

This step determines the extrinsic element values. The intrinsic data is generated by removing the extrinsic circuit contribution from the measured data. The ANN training is performed on the intrinsic part of the data.

The default extraction, automatically determines the extrinsic circuit values in two steps, the capacitance extraction and the inductance and resistance extraction. Each step allows you to inspect the results and overwrite the values, if required.

Execute Default Extraction workspace comprises three tabs:

- Extract Capacitance
- Extract Inductance and Resistance
- Generate Intrinsic Data.

Each tab is detailed in the subsequent content.

Extract Capacitance

Select Execute Default Extraction from the DynaFET Extraction Package window.

The model with default values is displayed in the workspace area. The page is ordered by the typical steps. First the capacitance values are displayed versus frequency. This allows you to select a frequency value where the capacitance is constant, using this value to select the Extraction Frequency in step 2. The final step is to Extract the values. The extracted values are displayed in the table and can be manually edited, if desired.

The C values can be exported/imported to a file by selecting the appropriate buttons.

DynaFET Extraction Package	the second se	
File Help		
Ta a Co Ka Star Running Mode: Meas	/ement *	
Project A Data Acquisition	Execute default extraction	
DC Series Resistance	Extract Capacitance Extract Inductance and Resistance Generate Intrinsic Data	
Cold-FET SP	Step 1: Display Capacitance	
Broadband SP for model validation	Page 1	
Input NVNA Data	Compac CON up Eran	
De-embedding Extraction of Extrinsic Elements	CdsmanCON vs Freq	
Execute default extraction		
Input of Custom values Intermediate review	Step 2: Select Extraction Frequency	
Intrinsic elements vs frequency Root model state functions vs bias	Frequency [Hz] 10G •	
 ANN model generation 		
Qg Qd	Step 3: Extract Parasitic Capacitance	
Ig	0	
 Model Validation 	Select	
DC SP	Extract	
	Manual Edit	
	Cvalues	
	Cgsman (F) 2.9e-15	
	Cgdman [F] 3e-15	
	Cdsman (F) Se-15	
	Cgsxo [F] 2e-15	
	Cpdvo [F] 0	
	Cdsext [F] 1.18e-14	
	Import	Export

Extract Inductance and Resistance

In this step, the Inductance and Resistance values are extracted from the data. The frequency range, where the data is extracted is limited to the range set in Step 1.

1. Click to plot the Z-parameters versus frequency, as depicted below.



2. Select a frequency range over which the real parts of Z12 are relatively independent and where the imaginary terms of Z11/Z22 are linear with respect to frequency. If these assumptions are incorrect, you need to try other bias settings for the Cold FET measurements.

Step 2 executes the automatic extraction and displays the values in the fields, where they can be manually edited.

The R and L values can be exported/imported to a file by selecting the appropriate buttons.

ID Dynaff E Extraction Package III III III III III III III III III I
Project Plata Acquisition DC Series Resistance Pinched-off 5P Boodband S Platmodel validation De embedding Extract of a Datainaic Elements Step 2: Extract of Acute Resistance Mex 362 Sec Se

Generate Intrinsic Data

When the extrinsic elements are satisfactorily determined, the Generate Intrinsic Data page is used. The workspace lists a summary of the extracted values. It also provides the option of only generating a subset of the data to reduce the generation time. It is up to you to keep track if changes to the data require a re-generation.



Generate Intrinsic Data workspace showing circuit element values and topology. Alternatively, you can select the **Input of Custom Values** page.



Input of Custom Values page allows manual override of all the values. Values can be set to any arbitrary value (for instance, determined by an alternative fitting process). Also, by setting element values to zero the topology can be modified effectively.

You need to assess the quality of the fit to the model and potentially modify the parasitic topology or extracted values. This assessment is done at each extraction step and after the intrinsic model fitting. The next step (intermediate review) provides an early feedback describing how well the model is fitting the measured data. After the intermediate review using the Root model, you are required to modify the parasitic values.

Intermediate Review

In the intermediate review step, a Root model is generated. The results can be used as a quick method to ascertain the quality of the data without the relatively long ANN training cycle.

NOTE

It is recommended to execute this step before NVNA measurement of GaN devices outside IC-CAP, if you have a concern that device might degrade during the DC and S-Parameter measurement sequences.

To perform intermediate review:

- 1. Select Intrinsic elements vs frequency from the DynaFET Extraction Package window.
- 2. Select the value of Vg and Vd.
- 3. Select the extraction frequency.
- 4. Set the bias point for Rgs0 extraction (typically the application operating point)

- 5. Click to extract RGs0 and Alpha values. Review the extracted data and modify (if required) before proceeding to the next step.
- 6. Generate the intrinsic data.

/gs [V]	Vds [V]			Selected Bias	
-0.8	▲ 2.0		*	-0.4,1.4	
-0.6	2.2			1.2,2.4	
-0.4	2.4			1.6,3.6	
-0.2	2.6			1.6,2.6	
0.0	2.8			1.6,4.0	
0.2	3.0		Add	1.6,4.4	
0.4	3.2		Perrove		
0.6	3.4		E		
0.8	3.6				
1.0	3.8				
1.2	= 4.0				
1.4	4.2				
2p 2: Select Extraction	on Frequency				
	1				
requency 3.7G -	J				
requency 3.7G •	nd Alpha				
ep 3: Extract Rgs0 ar	d Alpha				
requency 3.7G	nd Alpha	To be extract	ted		
ep 3: Extract Rgs0 ar ias Point for Rgs0 Extra /gs -0.6	n d Alpha	To be extrac Rgs0 [Ohm]	ted 2.96017		
ep 3: Extract Rgs0 ar as Point for Rgs0 Extra gs 0.6 ds 3	nd Alpha	To be extract Rgs0 [Ohm] Alpha	ted 2.96017 1		
ep 3: Extract Rgs0 ar as Point for Rgs0 Extra gs -0.6 rds 3	nd Alpha	To be extract Rgs0 [Ohm] Alpha	ted 2.96017 1		
ep 3: Extract Rgs0 ar as Point for Rgs0 Extra gs =0.6 ds 3 ep 4: Generate Intrin	nd Alpha ction [/]	To be extract Rgs0 [Ohm] Alpha	ted 2.96017 1		
ep 3: Extract Rgs0 ar as Point for Rgs0 Extra gs =0.6 ds 3 ep 4: Generate Intrin	nd Alpha ction [/] ssic Data	To be extract Rgs0 [Ohm] Alpha	ted 2.96017 1		
ep 3: Extract Rgs0 ar as Point for Rgs0 Extra gs =0.6 ds 3 ep 4: Generate Intrin	nd Alpha ction [/]	To be extract Rgs0 [Ohm] Alpha	ted 2.96017 1		



7. Click the Check icon (1) to perform data sanity check.

Review the data and check for discontinuities, unexpected behavior or changes indicating that the device is degraded or is not functioning as expected. If issues are found, they should be resolved prior to NVNA measurements or ANN model generation.

The review determines if the problem is:

- $^{\circ}$ $\,$ either with the measured data (noisy) or extracted values, or
- either due to incorrect selection of bias or frequency ranges where a particular parameter was fit or because the model topology does not reflect the topology of the actual device.

In such scenarios, you need to determine why the model does not fit and take appropriate steps to determine the parasitic values. For instance, poor fitting of only S11 indicates an error with the input (gate) resistance or the gate-source capacitance.

ANN Model Generation

Artificial Neural Network (ANN) is an information processing system with their design inspired by the studies of the ability of the human brain to learn from observations and to generalize by abstraction. ANN has the ability to model highly nonlinear relationships with multiple inputs and outputs.

The objective of the training procedure is to identify the functions $I_D Q_D$, $I_G Q_G$ from the set of DC, S-Parameter, and large-signal data measured at different temperatures. In the case of the drain current, dynamical variables (for instance, trap states voltages and junction temperatures) are computed from simple functions of the measured NVNA waveforms. The drain current constitutive relation for the model, as a function of V_{gs} , V_{ds} junction temperature, T_j , and trap states (f₁, f₂) and the new dynamical variables, is represented by an artificial neural network (ANN), trained using the waveforms as well as the DC and S-parameters, de-embedded from the extrinsic parasitic network, as targets.

Start ANN Training

To start the ANN training setting, do the following:

1. Select the ANN model generation from the Navigation pane, as depicted below. The overview pane by default

lists all the intrinsic data to be generated when the **Generate Training Data** button, *is pressed*. When the function is executed, the program samples the data and prepares it for the training procedure. Check boxes are included to allow only subsets of the data to be generated if necessary (to save time).

ANN model generation

Introduction	ANN Data Generation
à	
Data to be ge	nerated for ANN training
V Qg	
V Qd	
🔽 Ig	
V Id (DC)	
📝 Id (NVNA)

Once the training data is generated, the individual functional outputs can be trained.

2. Select Qg, Qd, Ig, Id from the DynaFET Extraction Package window. All Qg, Qd, Ig, Idpanes have similar features.

Each has a control bar and a display area, showing current settings.

Þ. m. 🔳 📝	1 🔄 🔹
ANN	
Max Iterations	2000
Stop Tolerance	0
# of Hidden Neurons	8
	Reset

The control functions are summarized in the following table.

Function	Description
	Starts the ANN training
Hel	Resumes the paused training session
	Allows to pause the training session
	Perform the test results using Sweep settings
	Displays the Plot results

••	Allows to modify settings

Check ANN Training Status

You can start the training by pressing the Start button, if settings do not require a modification. When the training starts, the progress window is display (depicted below), displaying what is being trained, a graphical view of the training error (s), numerical value and display, a graphical representation of the progress, and the time spent.

	Training Name	Training Error History	Current Error / Target Error	Training Progress	Training Iteration	Time
1	DynaFET_Qg		0.075386 / 0		80 / 2000	00:01:09
2	DynaFET_Id		5.15379 / 0		50 / 2000	00:00:56
3	DynaFET_Qd		0.003254 / 0		110 / 2000	00:00:18
4	DynaFET_Ig		0.009814 / 0		190 / 2000	00:00:13

Multiple training sessions can run simultaneously by simply navigating to other pages and starting the training sequence.

Individual sessions can be paused on their page, or all of the training can be stopped by pressing from the main DynaFET control bar. By default, the target error is set to 0.0 and the number of iterations is set to 2000, so the training always run for the complete number of iterations. The status window also displays textual information.

After generating the data, the **Test ANN Training** displays the modeled data and the measured in a plot. The data can then be inspected for errors.

The **Sweep ANN training** evaluates the model at data points other than those used to create the data (for instance, smoothness). If there are problems, the model can be retrained after adjusting training parameters. It is important to check the model with swept inputs because if the model is over trained, the result could be ringing in the model with large mismatch at the bias points that do not exist in the measured data. These sweep parameters are available by pressing the Settings button. The first tab page contains the basic settings that are displayed on the main workspace window.

Qd Adv	vanced Setting		? ×
Basic	Weighting	Sweep	
ANN			
Max I	terations	2000	
Stop 1	Tolerance	0	
# of ⊦	Hidden Neurons	10	
		Reset	
		OK	Cancel Apply

Basic properties in the Settings dialog box.

The properties are described in the table below.

Property	Description
Max Iterations	Indicates the maximum number of iterations the training can execute to reach the Stop Tolerance.
Stop Tolerance	Indicates that the training is complete, when the error term is defined as: $E = \sum_{k=1}^{\# of \ waveforms} (W_{l} \cdot E_{k,l} + W_{2} \cdot E_{k,2})$
# of Hidden Neurons	Indicates the number of neurons for each of the two levels in the neural net. Increasing this value could improve fit to complex output values at the expense of more training time.

The second tab page allows you to apply different weighting levels to the data set. This can be useful to fit the model better in regions that are important to the model's application.

# of Weight Se	egments Used	1			Reset	Sample N in Xaxi
	from		to	<dqd dvgs=""></dqd>	<dqd dvds=""></dqd>	Show Range
Segment 1	1	1e9		1.0	1.0	Set Range
Adjoint Scale						
Adjoint Scale		1		2 Rese	:t	
Adjoint Scale dQd/dVgs (Ii	mag(Y21)/w)	1 -0.0998454	0.052593	2 Rese 36	et	

Weighting function advanced settings allow you to give emphasis to some regions of data.

To determine the segment, press the plot button that displays the appropriate data in a window. The data is numbered sequentially. The **# of Weight Segments Used** can be incremented to add additional segments, which can then have different weights applied. You can highlight a segment and press **Show Range** to display it as a blue box on the plot. Using the mouse to select and drag a rectangle displays a white box on the plot to define a new range. Pressing **Set Range** sets the selected segment to that range. The weighting function for each term can then be manually set in the appropriate field. The **Sample N in Xaxis** restricts the amount of data plotted for large datasets.

The range in the Adjoint values can be limited in range by setting the values in the array at the bottom of the dialog box. The pertinent values for the particular function are displayed and you can double-click on each field and enter a new value. These values limit the data used in training to those data points whose adjoint value is within the Adjoint Scale range.

The third tab page is used to set the properties for the Sweep ANN Training function. The Vd and Vg sweep parameters set the values of biases to use, the temperature Tj sets the temperature for the simulation and the Option **With ANN Extrapolation** allows the model to be extrapolated beyond the training range. The **Parameters for 2nd Order Extrapolation** sets the weights (forVg, forVd) and exponential factor (alpha) in the extrapolation equation.

		Vg [V]	
Start	-2	Start	-5
Stop	10	Stop	1
# of Points	25	# of Points	6
Step	0.5	Step	1.2
Sweep Order	2	Sweep Order	1
Parameters	for 2nd Order Extrapolation		

Sweep settings used by the Sweep ANN Training function. These settings are not used during the model training but only used to illustrate how well the model fits at bias points other than those used to train it.

ANN Training I D

The drain current model supports additional features. You can chose between a Complete Model (the default) or a Simplified Model.

Project Data Acquisition	Id			
DC Series Resistance	H I V C			
Cold-FET SP	Model			
Broadband SP for model validation	Complete Model			
Input NVNA Data	Complete Model			
De-embedding	Simplified Model			
 Extraction of Extrinsic Elements 	AND			
Execute default extraction	AUET			
Input of Custom Values	# of Hidden Neurons for Id_main 20			
Intrinsic elements vs frequency	# of Hidden Neurons for Id_aux 15			
Root model state functions vs bias	Max Iterations 200			
 ANN model generation 	Stan Tolarance			
Qg				
la la	Reset			
Id	AUALA Desembles DJ			
 Model Validation 	NVNA resamping [v]			
DC	Vgs Step 0.2			
SP	Vds Step 1			
	Vas Step 1 0.4			
	Vide Char 1 0 0			
	Vas step 1 0.2			
	Vgs Step 2 0.5			
	Vds Step 2 1			

The simplified model only fits over 1 temperature, reducing the training time and non-linear data measurement time (the DC and S-Parameters must still be measured at more than one temperature, however). The simplified model's ANN assumes a fixed dependence on temperature. You must supply the coefficient **Alpha_T**. Pressing the Tune button displays the effect of the alpha coefficient. You can manually set **Alpha_T** based on the plot fit. Once the value is selected, press Data Generation to create the data to be trained on, then press **Start ANN Training**.



Tuning Alpha_T by adjusting the slider to fit the data at 2 temperatures in the simplified model.

The Settings dialog for the drain current includes additional properties. The number of Hidden Neurons can be set for both the main drain current (Id_main) or for the drain current due to influence of the auxiliary variables (Id_aux). The Basic setting allows choosing the re-sampling values for the NVNA non-linear waveform data. The Output Weighting can be adjusted for both the DC component of the non-linear waveforms and the DC values from the DC SP for model generation data. Because of the large number of non-linear waveforms, their weighting is much less than for Id_DC, by default. As the Sweep function can only plot 2-dimensional sweeps, the Setting include values to fix the trap voltages.

The extrapolation variables include a flag, **ForceO**, which is used to tune the drain current at low V_{DS} . Setting a large value (i.e., 10) cause the parameter to have little effect. When the value is reduced below 1 (e.g., 0.5) the trained data is strongly coerced toward 0. Very small values (close to 0) should be avoided, as this can cause non-physical behavior.

After training, Test ANN training (

) displays how well the model fits against the measured data on which it was

trained while **Sweep ANN training** () interpolates between data points and extrapolates beyond. These settings just define the bias region, to create the information and the sweep is completely unrelated to training.

Model Validation

After generating the ANN model, you can run DC or SP model validation.

DC Model Validation

For DC model validation,:

1. Select **DC** from the Model Validation page in the navigation pane and select the temperature to be used.

DC	
Temperature Setting	

2. Click the Validation icon (💌).

The comparison between the simulated data and the previously measured data is displayed for validation.

3. If the data is generated, the plot windows can be re-opened using the Plot icon (

SP Model Validation

For SP model validation:

1. Select **SP** from Model Validation page in the navigation pane. The SP settings are displayed in the workspace area.

- M fr	n in d	
100		

Grayed out fields indicate that they cannot be edited.

SP					
Frequency [Hz]		Vd [V]		Vg [V]	
Start	500MEG	Start	3.0	Start	1.0
Stop	50G	Stop	5.1	Stop	2.0
# of Points	100	# of Points	2	# of Points	3
Step	500MEG	Step	2.1	Step	500m
Sweep Order	1	Sweep Order	2	Sweep Order	3

2. Click the Validation icon (

The comparison between the simulated data (S-parameters versus bias and frequency) and the previously measured data is displayed for validation.

3. If the data is generated, the plot windows can be re-opened using the Plot icon (${}^{ imes}$

E

ADS Model Distribution

The DynaFET model files can be found in the project's validation directory. These files can then be referenced by the ADS modelcard.

Extracting a DynaFET Model

This section describes the step-by-step instructions and test procedure to measure, extract, and generate a DynaFET model using the DynaFET Modeling Package. DynaFET model extraction procedure is classified into 16 steps:

- Step 1 Launching the DynaFET Extraction Modeling Package
- Step 2 Entering the Device information
- Step 3 Configuring the Hardware
- Step 4 Measuring the DC Series Resistance
- Step 5 Measuring the Pinched-off FET characteristics
- Step 6 Measuring the Cold-FET characteristics
- Step 7 Measuring the Broadband S-Parameters for model validation
- Step 8 Measuring the DC and S-Parameters for model generation
- Step 9 Bringing the NVNA data into the DynaFET Extraction Package
- Step 10 De-embedding the extrinsic test structure
- Step 11 Extracting the extrinsic element network from the data
- Step 12 Extracting Rgs0/Alpha
- Step 13 Reviewing the data using a Root model
- Step 14 Training the Artificial Neural Network
- Step 15 Validating the model
- Step 16 Accessing the model in Advanced Design System (ADS)

Step 1 – Launching the DynaFET Extraction Modeling Package

1. To start the program, from the **IC-CAP Main Window**, open the **Examples** folder and move to the model_files /mesfet/dynafet directory and select the DynaFET.mdl file.



- 2. Double-click the DynaFET icon in the **IC-CAP Main Window**, this displays a dialog box prompting for project location details.
- 3. Enter the project name and the directory, where the project is to be created
- 4. Click OK.
| Copy DynaFET Example Project | | | | | | |
|------------------------------|------------------|-----------|--|--|--|--|
| Project Location | | | | | | |
| Name | test | | | | | |
| Created in | C:/iccap_project | Browse | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | OK Cancel | | | | |

Step 2 - Entering the Device information

NOTE

To load previously stored set of device information, click **Import...** and select the respective file.

- 1. Enter a string for the Device ID and the Chip ID. If required, values can be entered for the Process, Mask, and Wafer.
- 2. Enter the total gate width in meters and the # of fingers for the device.
- 3. Enter the channel resistance in Ohm-mm and the thermal resistance (in degree C / Watt) and thermal time constant (in seconds).



The device information can be stored in a file, so it can be conveniently loaded in other projects. To load the information, click **Export...** and provide the file name.

DynaFET Extraction Package				- • ×			
File Help							
📊 🐯 🕢 🞉 🤓 Running Mode (Measurement. 🔹							
Project Data Acquisition DC Series Resistance Pinched-off SP Cold+FET SP Broadband SP for model validation DC CE for an el la monstrial demonstrial	Project			Browse			
Input NVNA Data	Device Info						
De-embedding Estaction of Estimaic Elements Escotte default estaction Escotte default estaction Internation enternets vi frequency Root model state functions vb ias ANN model generation Q Q Q d Ig B Model Validation DC SP	ements Device ID Action Chip ID Process sfrequency Mask Wafer Total Gate With [# of Frigers Richan [Ohmen Rich [deg C/ Thermal Time Constant	device_01 drip_01 0.0001 2 0.000155 1450 0.0001	100.0 [un]				

Step 3 – Configuring the Hardware

- 1. Setup the hardware with a PNA-X NVNA and a power supply. The PNA-X should be calibrated over the frequency range of interest with the power and attenuated settings, and the average values.
- 2. Save the instrument state after making all the settings.
- 3. Click on Data Acquisition in the Navigation pane and the Instrument Setting tab. Open the Hardware Window (

) and add an interface and rebuild the instrument list, if necessary. Select the power supply and press **Configure...** and assign the SMU1 and SMU2 names.

- 4. Close the Hardware window and download the instrument information by pressing
- 5. In the middle column, select the DC Source/Monitor and the NWA from the pull down lists.
- 6. Select each instrument and set any property values in the table. It is recommended to use an integration time of at least Medium. In the NWA settings, set the instrument state and other values to match the state settings or set the property "Use PNA Calibration Settings" to "Yes".
- 7. Click the **Measurement Setting** tab and modify the required fields.

Step 4 – Measuring the DC Series Resistance

- 1. Select the DC Series Resistance page from the Data Acquisition parent page in the Navigation pane.
- 2. Lower both probes onto shorting structures.
- 3. Select Measure and press the Measure icon
- 4. Press the Plot icon and inspect the plots. The I-V curves should be straight lines with minimal noise.

Step 5 – Measuring the Pinched-off FET characteristics

- 1. Select the Pinched-off SP page from the Data Acquisition parent page in the Navigation pane.
- 2. If required, modify the Frequency sweep or bias settings.
- 3. Select Measure and press the Measure icon
- Press the Plot icon and inspect the plots. The S-Parameters should be smooth and appear similar to those shown below.



5. Press the **Save** icon **to** save the data.

Step 6 – Measuring the Cold-FET characteristics

- 1. Select the Cold-FET SP page from the Data Acquisition parent page in the Navigation pane.
- 2. If required, modify the Frequency sweep or bias settings.



4. Press the **Plot** icon and inspect the plots. The S-Parameters should be smooth and appear similar to those shown below.



5. Press the **Save** icon **to** save the data.

Step 7 – Measuring the Broadband S-Parameters for model validation

- 1. Select the **Broadband SP for model generation** page from the **Data Acquisition** parent page in the **Navigation** pane.
- 2. If required, modify the Frequency sweep or bias settings. Choose bias points that is different from those used to extract the model.
- 3. Select Measure and press the Measure icon
- 4. Press the **Plot** icon and inspect the plots. The S-Parameters should be smooth and appear similar to those shown below.



5. Press the **Save** icon **I** to save the data.

Step 8 - Measuring the DC and S-Parameters for model generation

- 1. Select the **DC SP for model generation** page from the **Data Acquisition** parent page in the **Navigation** pane.
- 2. Set the power, breakdown, and compliance values associated with the device.
- 3. If required, press the **Advanced Setting** button and set additional parameters related to the adaptive step and bias soak feature.
- 4. Set the appropriate temperature value for the actual device temperature.

NOTE

The temperature settings are managed manually.

- 5. Set the number of regions and the bias sweep and options for each region.
- If the safe operating region is not known, select the DC Only option and slowly approach the region boundaries. It
 may be necessary to use a sacrificial device.
- 7. Select Measure and press the Measure icon
- 8. Press the **Plot** icon and inspect the plots. The DC-IV curves should cover the device's operating region. The S-Parameters should be smooth and appear similar to those shown below.







9. Press the **Save** icon **to** save the data.

Step 9 – Bringing the NVNA data into the DynaFET Extraction Package

- 1. Select the Input NVNA Data page from the Data Acquisition parent page in the Navigation pane.
- 2. For each data set, enter the corresponding temperature the data was acquired at.
- 3. Press Get File... and select the NVNA waveform data file.
- 4. Enter the DC series resistance of the NVNA setup.

Step 10 – De-embedding the extrinsic test structure

- 1. Select the **De-embedding** page from the **Navigation** pane.
- 2. Toggle the check boxes for either the Add Open/Short or Add Manifold settings.
- 3. Double-click on each red box on the schematic and select the corresponding S-Parameter (s2p) file.
- 4. Check that II of the check boxes in the Data to be de-embedded section is checked.
- 5. Click 💌 to de-embed the data files.
- 6. Click if to plot the de-embedded data. Inspect the data for unusual behavior.

Step 11 - Extracting the extrinsic element network from the data

- 1. Select Execute default extraction from the Extraction of Extrinsic Elements page in the Navigation pane.
- 2. Select the Extract Capacitance tab page.
- 3. Click the plot button ¹ to display the capacitance values versus frequency.
- 4. Using the plots to find a suitable region where the capacitance is independent of frequency, select an extraction frequency value from the pull down list.
- 5. Click to extract the values.
- 6. Select the Extract Inductance and Resistance tab.
- 7. Select a frequency range to extract the resistances and capacitors.
- 8. Click with to extract the values.
- 9. Select the Generate Intrinsic Data tab page.
- 10. Ensure that both DC SP for model generation and NVNA checkboxes are selected.
- 11. Click the Generate Intrinsic Data button

Step 12 – Extracting Rgs0/Alpha

- 1. Select the **Intrinsic elements vs frequency** page under the **Intermediate Review parent** page in the **Navigation** pane.
- 2. Select Vgs and Vds values and add them to the **Selected Bias** column.
- 3. Click the plot button ¹ to display the intrinsic values.
- 4. Using the plots to determine a suitable frequency where the intrinsic values are frequency independent, set the **Extraction Frequency**.
- 5. Set an appropriate bias for Rgs0 and Alpha (typically an operating point where the device is used).
- 6. Click 🔛 to extract the values.
- 7. Click to Generate Intrinsic Data.

Step 13 - Reviewing the data using a Root model

- 1. Select the **Root model state functions vs bias** page under the **Intermediate Review parent** page in the **Navigation** pane.
- 2. Specify a bias to generate the Root model.

- 3. Click to extract the model. The state functions are displayed.
- 4. Click is to generate the Root model data to compare to the measured data.
- 5. Inspect the plots for unusual results that might indicate device issues (e.g., degradation).

Step 14 - Training the Artificial Neural Network

- 1. Select the ANN model generation page from the Navigation pane.
- $\ \ 2. \ \ Check \ that \ all \ of \ the \ functions \ are \ checked \ for \ data \ generation.$
- 3. Click to Generate Training Data.
- 4. For each Qg, Qd, Ig, Id, go to the appropriate page and click 💌 to start the training.



NOTE

Multiple ANN trainings can run in parallel.

- 5. Click for the trained ANN versus the measured data it was trained on.
- 6. Press to sweep the ANN training over new bias ranges based on the Settings->Sweep tab page.

Step 15 - Validating the model

- 1. Select **DC** or **SP** pages from the **Model Validation parent** page in the **Navigation** pane.
- 2. If rquired, modify the frequency and bias ranges.
- 3. Click i to generate the data and display the plots.

Step 16 - Accessing the model in Advanced Design System (ADS)

- 1. Copy the DynaFET_model.enc file from the project's validation directory to the ADS workspace data directory.
- 2. From the ADS schematic, add the DynaFET instance and model card from the Devices-JFET palette.
- 3. On the model card, set the parameter DynaModelFile to point to the file.